

Resource Summary Report

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JEOL: JEM-F200 F2 Transmission Electron Microscope

RRID:SCR_020175

Type: Tool

Proper Citation

JEOL: JEM-F200 F2 Transmission Electron Microscope (RRID:SCR_020175)

Resource Information

URL: <https://www.jeolusa.com/PRODUCTS/Transmission-Electron-Microscopes-TEM/200-kV/JEM-F200-F2>

Proper Citation: JEOL: JEM-F200 F2 Transmission Electron Microscope (RRID:SCR_020175)

Description: Transmission scanning electron microscope that offers Cold Field Emission Gun and dual Silicon Drift Detectors

Resource Type: instrument resource

Keywords: Jeol, JEOL, Transmission Electron Microscope, Instrument Equipment, USEDit,

Availability: Commercially available

Resource Name: JEOL: JEM-F200 F2 Transmission Electron Microscope

Resource ID: SCR_020175

Alternate IDs: Model_Number_JEM-F200 F2

Record Creation Time: 20220129T080349+0000

Record Last Update: 20260905T132910+0000

Ratings and Alerts

No rating or validation information has been found for JEOL: JEM-F200 F2 Transmission Electron Microscope.

No alerts have been found for JEOL: JEM-F200 F2 Transmission Electron Microscope.

Data and Source Information

Source: [SciCrunch Registry](#)

Usage and Citation Metrics

We have not found any literature mentions for this resource.